

corrections thereto, applicants submit herewith a Substitute Specification, along with a marked-copy of the original specification for the Examiner's convenience. Applicants submit that the substitute specification includes no new matter. Therefore, entry of the Substitution Specification is respectfully requested.

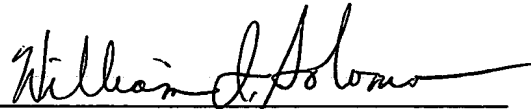
The claims have also been amended to more clearly describe the features of the present invention.

Entry of the preliminary amendments and examination of the application is respectfully requested.

To the extent necessary, Applicants petition for an extension of time under 37 CFR § 1.136. Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to the Deposit Account No. 01-2135 (Case No. 503.38156X00) and please credit any excess fees to such Deposit Account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP



William I. Solomon  
Registration No. 28,565

1300 North Seventeenth Street  
Suite 1800  
Arlington, VA 22209  
Tel.: 703-312-6600  
Fax.: 703-312-6666

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Enclosures



A METHOD OF PROCESSING SPECIMENS, AN APPARATUS THEREFOR AND A  
METHOD OF MANUFACTURE OF A MAGNETIC HEAD

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BACKGROUND OF THE INVENTION

5 The present invention relates to a method of processing specimens by plasma etching, an apparatus therefor and a method of manufacture of a magnetic head using the same.

A specimen, such as a substrate of a semiconductor device, is subjected to etching processing, for example, using a chemical solution or by plasma etching. In such etching processing of the specimen, adequate care must be taken <sup>to prevent</sup> ~~against~~ corrosion of the specimen after etching processing.

10 <sup>an</sup> ~~As~~ such prior art <sup>is disclosed</sup> ~~anti-corrosion technique~~ <sup>for use the</sup> ~~after~~ etching processing of the specimen, there is <sup>in</sup> known, for example, JP-A Laid-Open No. 59-186326, wherein a residual chlorine compound, which is a corrosive substance remaining in a resist film and the like, is oxidized by ashing process for ashing the resist film using <sup>a</sup> plasma in a plasma processing chamber which is connected to an etching chamber and is maintained in <sup>a</sup> vacuum. Further, it is also known that by heating the specimen after etching ~~(process)~~ to a temperature above 200°C, evaporation of a residual chlorine substance, which is <sup>remaining in the specimen,</sup> ~~corrosive material~~ is promoted, thereby preventing corrosion of the substance after the etching process. Still another <sup>process</sup> ~~(prior art)~~ is disclosed in JP-A Laid-Open No. 25 61-133388, wherein a specimen to be treated after ~~[its]~~ etching ~~(process)~~ is taken out of an etching chamber, transferred to a heat treatment chamber, dried by ~~[a]~~ heated air, and then is taken out

of the heat treatment chamber to be rinsed and dried, thereby attempting to prevent corrosion of the specimen due to reaction with <sup>the</sup> atmosphere after [its] etching [process].

JP-A Laid-Open No. 2-224233 discloses a method of processing specimens, comprising: a first step of processing a <sup>laminated</sup> specimen [of lamination] which includes metals, each having a different ionization tendency, by gas plasma etching using a first gas plasma via a resist mask formed on the lamination in a first processing chamber; a second step of processing the specimen using a second gas plasma, which is formed in a gas atmosphere different from <sup>that of</sup> the first gas plasma in a second processing chamber, for removing the resist mask and residual corrosive substances formed in the first step and deposited on a surface of side walls of the lamination including different ionization metals; and a third step of rinsing the surface of the specimen which is exposed by the first and the second steps with at least one liquid for removing a remaining part of the residual corrosive substances deposited on the side wall of the lamination which could not have been removed by the second step. <sup>According to this method,</sup> wherein <sup>an</sup> in the first step, the specimen formed by laminating <sup>a</sup> Al alloy film and <sup>a</sup> TiW or TiN film is subjected to etching [process] via a resist mask in <sup>a</sup> vacuum using <sup>a</sup> gas plasma which contains chlorine; in the second step, the specimen is subjected to <sup>an</sup> <sup>a</sup> washing process using <sup>a</sup> gas plasma which contains chlorine; and in the third step, the specimen is rinsed in water, and wherein <sup>of</sup> the third step is comprised either one of the following four steps in order to remove a residual corrosive product remaining after the first step: (a) rinsing in water; (b) rinsing in water after

rinsing in alkaline liquid; (c) rinsing in water after rinsing in acid liquid; and (d) rinsing in water after rinsing in fluorine nitric acid.

A [prior art] method of etching a material for use in a thin film magnetic head, magnetic sensor and the like which contains Fe is disclosed in JP-A-4-107281. This method of etching the material which contains Fe is directed to etching such a material as Fe-containing<sup>an</sup> alloy formed on a surface of the specimen, and in particular, <sup>a</sup>(as) Fe-Si-Al alloy, and is comprised of the steps of: etching the specimen by reactive ion milling in chlorine gas by heating the specimen above 250°C and below a melting point thereof in<sup>a</sup> vacuum; a post treatment process for causing a residual substance remaining on the surface of the specimen completely to react with the chlorine gas by holding the specimen at a temperature above 250°C and by applying a chlorine ion shower to the specimen; and a pure water treatment process for dissolving and removing an etching product produced in the post treatment process by holding the specimen in pure water, wherein these steps are executed in <sup>the</sup>(this) sequence [of order] as described above.

However, there is a problem associated with the <sup>method</sup>[prior art] of JP-A-Publication No. 4-107281<sup>in</sup> that, when etching pure Fe, for example, of 3 μm thick, by argon ion milling for constructing a magnetic head, because [of] its etching rate (being)<sup>is</sup> approximately 150 Å/min., <sup>the</sup>[its] etching time (takes)<sup>is</sup> as long as 200 min. This is because that the number of <sup>incident</sup>ions [of incidence] controls <sup>the</sup>[its] etching rate. Therefore, in order to improve <sup>the</sup>(its) etching rate, the specimen is heated above 250°C, and the reactive ion milling

method is applied in <sup>an</sup> atmosphere of chlorine gas in JP-A Laid-Open No. 4-107281, thereby improving the etching rate

approximately to a level of 1000A/min. However, there arise <sup>in</sup> <sup>the</sup> <sup>the specimen may not be able to</sup> <sup>such</sup> problems, that, depending on <sup>the</sup> <sup>it</sup> type of specimen, <sup>it</sup> cannot withstand

5 a temperature above 250°C, thereby preventing application of the above-mentioned method in such a case. In particular, in the case

of etching <sup>(of)</sup> a lamination film which includes a ferromagnetic material such as NiFe alloy which is used in manufacture of a

magnetic head, if <sup>the</sup> <sup>(a)</sup> temperature of its specimen rises above 230°C,

10 <sup>the</sup> <sup>(a)</sup> magnetic property of <sup>the</sup> NiFe film is deteriorated, such that it cannot be recovered even when its temperature returns to normal, or <sup>(that)</sup> a re-magnetization process is required for recovering the initial magnetic property.

Further, in JP-A Laid-Open No. 4-107281, because the

15 specimen tends to corrode when left in <sup>the</sup> atmosphere after the reactive ion milling, a corrosion prevention process is proposed,

which includes a post treatment step for applying <sup>a</sup> chlorine ion shower to the specimen which is kept at a high temperature above 250°C and a pure water treatment step for submerging the specimen

20 in pure water after the post treatment. However, there are <sup>with this proposal as well, in</sup> <sup>such</sup> problems,

that a temperature above 250°C is required for the specimen once again, and <sup>(that)</sup> a complicated corrosion prevention sequence of the ion shower step followed by the pure water submersion step is required, thereby increasing the cost.

25 The above-mentioned complicated corrosion prevention procedure is considered to be necessary because <sup>the</sup> <sup>(that its)</sup> target specimen, which is <sup>an</sup> Fe-Si-Al alloy, contains two different metals

having a largely different ionization tendency from each other,  
 and therefore, ~~is highly corrosive as described in JP-A Laid-~~  
 Open No. 2-224233.

Further, the lamination film thereof, as formed and to be  
 5 processed in <sup>the</sup> manufacture of the magnetic head, generally includes  
 an oxide film of NiFe alloy, alumina, silicon oxide or the like,  
 thereby allowing for a reaction product resulting from etching  
 of these films by milling, plasma etching or the like to deposit  
 on the surface of <sup>the</sup> side walls of the etched lamination. This deposit  
 10 film on the sidewalls causes a problem when etching the lamination  
 continuously by impeding a subsequent etching process, thereby  
 rendering it difficult to carry out a vertical processing.

#### SUMMARY OF THE INVENTION

15 An object of the invention is to provide for a method of  
 processing a specimen <sup>formed</sup> of <sup>a</sup> lamination film which includes <sup>a</sup> Ni-Fe  
 alloy, <sup>characterized in</sup> featuring that the lamination can be etched at an improved  
 etching rate and at a low temperature which prevents break-down  
 of the device, <sup>so</sup> that a simple and low cost corrosion prevention  
 20 treatment is provided, and, at the same time that, the deposition  
 film on the side walls can be efficiently removed, thereby ensuring  
<sup>that a</sup> (the) continuous and vertical etching of the lamination <sup>will</sup> (to) be  
 carried out, and to provide for an apparatus therefor and also  
 a method of manufacture of a magnetic head using the same.

25 The feature of the present invention resides in combining  
 a step of plasma etching of a specimen, such as a magnetic pole  
 of a magnetic head, which is formed of Ni-Fe alloy, using a

relatively high density plasma source and a gas which contains chlorine and/or fluorine nitric acid, and a step of rinsing <sup>the specimen</sup> in <sup>a</sup> liquid and drying <sup>it</sup> immediately (to be carried out) after the etching processing.

5           The above-mentioned high density plasma source refers to an induction coupling type plasma apparatus, helicon type plasma apparatus, two-frequency excitation parallel plane type plasma apparatus, microwave type plasma apparatus and the like, which can generate <sup>a</sup> plasma having a saturated ion current density of approximately 1-10 mA/cm<sup>2</sup>. This type of apparatus has a plasma density as high as 10 to 100 times compared to low density plasma of <sup>conventional</sup> prior art milling and parallel plane type apparatuses. Further, in these types of high density plasma sources, another high frequency power source separate from the high frequency power source for plasma generation is provided for the specimen stage, which can be controlled independently of an ion energy of incidence on the specimen. When this plasma source is applied, because of an increased number of <sup>incident</sup> ions [of incidence], even if <sup>the incident</sup> setting of ion energy [of incidence] is decreased <sup>to</sup> as low as (to a) 20 [value of] 50-500 eV, that is, 1/2 to one tenth of the values for the milling method, and the temperature of the specimen is decreased, a high etching rate becomes possible. For example, at a temperature of 40°C of the specimen and at <sup>an</sup> ion energy of 300 eV, an etching rate of 100 nm/min can be realized. If the 25 temperature of <sup>the</sup> specimen is in the range of 40 to 60°C, there is another advantage <sup>in</sup> that the design of the specimen stage can be simplified contributing to the reduction of cost.

Further, because of a shallow penetration depth of <sup>the</sup> ~~bombarded chlorine ions into~~ <sup>the</sup> Ni-Fe alloy layer due to a low <sup>according to</sup> bombardment ion energy in the high density plasma processing ~~(of)~~ the invention, and because ~~(that)~~ Ni and Fe are identical metals  
 5 having an identical ionization tendency which is immune to the corrosion mechanism due to different ionization tendencies, as described above, ~~(which allows for)~~ <sup>can</sup> a corrosion prevention ~~(to)~~ be realized by simply removing residual chlorine components deposited on the surface layer of the specimen, thereby providing  
 10 for a simple and low cost corrosion prevention means of the invention.

Still further, the lamination layer which is prepared for manufacture of a magnetic head includes, in addition to the Ni-Fe alloy layer, various other layers, such as <sup>a</sup> ~~(an oxide)~~ layer of alumina or silicon oxide, <sup>a</sup> photo resist layer and the like, which must be  
 15 processed by etching using high density plasma. During ~~(these)~~ <sup>the</sup> etching processing of the lamination layer, ~~(there occurs that)~~ the Ni-Fe alloy layer is exposed to plasma from the under-layer, or ~~(that)~~ using the Ni-Fe alloy layer itself as a mask, the oxide film  
 20 layer or the like is etched <sup>in</sup> ~~(in)~~ this instance also, <sup>the</sup> Ni-Fe alloy layer is exposed to a chlorine or fluorine plasma atmosphere, thereby needing a post etching treatment for corrosion prevention of the specimen. The corrosion prevention treatment by means of liquid rinsing according to the invention is effective to these  
 25 etching steps described above.

Furthermore, during etching of the lamination layer for manufacture of a magnetic head, a reaction product tends to



deposit on both sidewalls of the lamination layer to be etched.

Therefore, there arises a problem<sup>in</sup> that this reaction product deposited on the both sidewalls prevents a subsequent etching process from being continued, thereby impeding the continuous and vertical etching of the lamination layer. However, according to the invention, ~~this~~<sup>these</sup> reaction product deposits can be removed easily by the liquid rinsing treatment immediately after etching. Therefore, if an etching unit and a liquid rinsing/drying unit are provided in combination in one apparatus allowing for their continuous operation and treatment, and if this liquid rinsing treatment is inserted between each etching processing, an efficient and continuous etching can be achieved in one single apparatus.

More specifically, the instant invention provides for the following methods and apparatuses therefor.

The invention provides for a method of processing a specimen<sup>formed</sup> of<sup>a</sup> lamination layer which includes at least one layer of Ni-Fe alloy or Ni-Fe-Co alloy formed on a substrate, comprising: a first step for etching the lamination layer by<sup>a</sup> gas plasma<sup>including</sup> [with] a gas which contains chlorine at a temperature of the specimen below 200°C in an etching chamber; a second step of removing a residual chlorine compound which is deposited on a sidewall of the lamination layer which is exposed by the first step, by rinsing the same in at least one liquid; and a third step of drying the side wall thereof after rinsing.

The invention, further, provides for the<sup>above-referenced</sup> method of processing the specimen<sup>(according to the above)</sup>, wherein the second

step is executed continuously after the first step.

The invention provides for the method of processing the specimen, wherein the gas plasma is produced using at least one species of gas selected from the group consisting of  $\text{Cl}_2$ ,  $\text{BCl}_3$ ,  
 5 Ar and  $\text{O}_2$ , or <sup>a</sup>(in) combination thereof.

The invention, further, provides for the <sup>foregoing</sup> method of processing the specimen, wherein the second step of liquid rinsing is comprised of one or more of the following steps:

- (A) a pure water rinsing;
- 10 (B) water rinsing after alkaline liquid rinsing;
- (C) water rinsing after acid liquid rinsing;
- (D) water rinsing after fluorine nitric acid rinsing (resist developer solution TMAH); and
- (E) water rinsing after neutral detergent cleaning.

15 Further, the invention provides for the <sup>foregoing</sup> method of processing the specimen, wherein the third step of drying is executed at a temperature below  $200^\circ\text{C}$ .

Still further, the invention provides for the <sup>foregoing</sup> method of  
 20 processing the specimen, wherein <sup>the temperatures of</sup> the liquids used are controlled  
 [of their temperatures].

Furthermore, the invention provides for the method of processing the specimen, wherein the lamination layer of the specimen includes as other layers at least one of the following  
 25 layers which are to be subjected to gas plasma etching in the processing chamber:

- (A) a photo resist layer;

(B) alumina ( $\text{Al}_2\text{O}_3$ ) layer;

(C) silicon oxide layer;

(D) Cu layer; and

(E) Ta layer.

5

Furthermore, the invention provides for the method of processing the specimen, wherein the substrate is <sup>formed of</sup>  $\text{Al}_2\text{O}_3$  /TiC [substrate], on which substrate <sup>a</sup> Ni-Fe alloy or Ni-Fe-Co alloy layer is formed, which is etched by gas plasma in the processing chamber.

10

The invention provides for an apparatus for etching a specimen <sup>having a</sup> [of] lamination layer formed on a substrate using gas plasma in a processing chamber, comprising: an etching process chamber to which a gas is supplied to produce <sup>a</sup> plasma, and the lamination layer having more than two layers including at least one layer of Ni-Fe alloy or Ni-Fe-Co alloy formed on the substrate is etched therein at a temperature of the specimen below  $200^\circ\text{C}$ ; a rinsing unit for rinsing in a liquid a portion of the lamination layer including the Ni-Fe alloy and is exposed to <sup>the</sup> atmosphere by the etching process; and a dryer <sup>the</sup> unit for drying the portion of the lamination layer including <sup>the</sup> Ni-Fe alloy which is exposed, wherein the lamination layer of Ni-Fe alloy which is dried is further subjected to subsequent etching using <sup>a</sup> gas plasma.

15  
20

The present invention also provides for an apparatus for processing a specimen, comprising: an atmospheric loader; a vacuum transport chamber with a vacuum transport robot provided therein; <sup>(an)</sup> unload and <sup>(a)</sup> load lock chambers which connect between the atmospheric loader and the vacuum transport chamber; and an

25

etching process chamber of the etching process apparatus which is connected to the vacuum transport chamber, wherein the atmospheric loader is provided with a rinsing cup, hot plate and the like of the rinsing and drying unit [described above] connected thereto.

According to another aspect of the invention, a plurality of etching chambers are provided in the apparatus for processing the specimen.

According to still another aspect of the invention, a method of manufacture of a magnetic head having [a structure of] an upper magnetic pole and a lower magnetic pole disposed opposite thereto [is provided, the method] is comprised of the steps of: forming a lamination layer including an upper photo resist layer, a hard mask layer made of  $\text{SiO}_2$  or alumina, a lower photo resist layer and a seed layer made of Ni-Fe alloy or Ni-Fe-Co alloy; etching the hard mask layer by plasma processing using the upper photo resist layer as a mask; further etching the lower photo resist layer by plasma processing using a gas which contains chlorine with the hard mask used as a mask such that a deep groove is formed until the seed layer is exposed in the bottom of the deep groove; removing a residual chlorine compound deposited on the surface of the seed layer which is exposed by rinsing<sup>at</sup> with a liquid; drying the rinsed surface; and after that, embedding<sup>a</sup> Ni-Fe alloy into the deep groove which makes contact with the seed layer.

According to<sup>a</sup> still<sup>further</sup> [more] aspect of the invention, a method of manufacture of a magnetic head having a structure of an upper magnetic pole and a lower magnetic pole disposed opposite thereto

[is provided, the method] is comprised of the steps of: forming a lamination layer including a seed layer made of Ni-Fe alloy or Ni-Fe-Co alloy, an upper magnetic pole made of Ni-Fe alloy in close contact with the seed layer, a gap layer of an oxide film in close contact with the seed layer, and a shield layer made of Ni-Fe alloy in close contact with the gap layer; etching the seed layer using the upper magnetic pole as a mask with a gas which contains chlorine by plasma etching; and after that, removing a residual chlorine compound using a liquid.

Further, according to the invention, a method of manufacture of a magnetic head which has a structure of an upper magnetic pole and a lower magnetic pole disposed opposite thereto [is provided, the method] is comprised of the steps of: forming a lamination layer which includes a seed layer made of Ni-Fe alloy or Ni-Fe-Co alloy and an upper magnetic pole made of Ni-Fe alloy connected with the seed layer, a gap layer made of an oxide film in close contact with the seed layer, and a shield layer made of Ni-Fe alloy in close contact with the gap layer; etching the seed layer; etching the gap layer by plasma etching using the upper magnetic pole as a mask and with a gas which contains chlorine or fluorine; and then removing a residual chlorine compound by rinsing with a liquid.

According to<sup>a</sup> still further aspect of the invention, a method of manufacture of a magnetic head having a structure of an upper magnetic pole and a lower magnetic pole disposed opposite thereto [is provided, the method] is comprised of the steps of: forming a lamination layer which includes a seed layer made of Ni-Fe alloy

or Ni-Fe-Co alloy and an upper magnetic pole made of Ni-Fe alloy  
connected with the seed layer, a gap layer made of an oxide film  
in close contact with the seed layer, and a shield layer made of  
Ni-Fe alloy in close contact with the gap layer; etching the seed  
5 layer; etching the gap layer; trim-etching the shield layer using  
the upper magnetic pole as a mask and with a gas containing chlorine  
by plasma processing; and then removing a residual chlorine  
compound by rinsing with a liquid.

According to still another aspect of the invention, a method  
10 of manufacture of a magnetic head having a structure of an upper  
magnetic pole and a lower magnetic pole disposed opposite thereto  
[is provided, the method] is comprised of the steps of: forming a  
lamination layer which includes a seed layer made of Ni-Fe alloy  
or Ni-Fe-Co alloy and an upper magnetic pole made of Ni-Fe alloy  
15 connected with the seed layer, a gap layer made of an oxide film  
in close contact with the seed layer, and a shield layer made of  
Ni-Fe alloy in close contact with the gap layer; etching the seed  
layer, the gap layer and the shield layer, respectively, using  
the upper magnetic pole as a mask by plasma etching exclusively  
20 in a vertical direction; and executing a corrosion prevention  
treatment to remove a residual chlorine compound deposited on an  
etched surface.

In the method of manufacture of a magnetic head according  
to the invention, the gap layer is processed by plasma etching  
25 with a gas which contains chlorine or fluorine, and the seed layer  
and the shield layer are processed by plasma etching with a gas  
which contains chlorine and argon gases, and further the corrosion

prevention treatment is executed by rinsing using a liquid.

The invention provides for a method of manufacture of a

magnetic head having a structure of an upper magnetic pole and a lower magnetic pole disposed opposite thereto, the method <sup>being</sup> is <sup>^</sup>

5 comprised of the steps of: forming a lamination layer which includes a seed layer made of Ni-Fe alloy or Ni-Fe-Co alloy and an upper magnetic pole made of Ni-Fe alloy connected with the seed layer, a gap layer made of an oxide film in close contact with the seed layer, and a shield layer made of Ni-Fe alloy in close  
10 contact with the gap layer; etching the seed layer and the gap layer continuously by plasma etching using the upper magnetic pole as a mask; and then executing a corrosion prevention treatment for removing a residual chlorine compound deposited on an etched surface.

15 The invention provides for a method of manufacture of a magnetic head having a structure of an upper magnetic pole and a lower magnetic pole disposed opposite thereto, and in particular, a method of manufacture of the upper magnetic pole thereof, the method thereof <sup>being</sup> is comprised of the steps of: forming a lamination  
20 layer which includes an upper magnetic layer made of Ni-Fe alloy, and a mask layer made of an oxide film such as photo resist or alumina, a silicon oxide and the like; etching the upper magnetic pole layer by plasma etching with the mask layer used as <sup>a</sup> its mask; and then executing a corrosion prevention treatment for removing  
25 a residual chlorine compound deposited on an etched surface.

Further, the invention provides for a method of processing an upper magnetic pole of a magnetic head having a structure of

an upper magnetic pole and a lower magnetic pole disposed opposite thereto, the method <sup>being</sup> ~~[is]~~ comprised of the steps of: forming, from the above,

- (A) a photo resist film,
- 5 (B) an oxide layer such as alumina, silicon oxide or the like,
- (C) an upper magnetic pole layer made of Ni-Fe alloy,
- (D) a seed layer made of Ni-Fe-Co alloy for bonding Ni-Fe alloy,
- (E) a gap layer made of an oxide film such as alumina, silicon oxide or the like, and
- 10 (F) a shield layer made of Ni-Fe alloy;

executing the following plasma process steps continuously

- (1) etching the oxide film layer using the mask layer as <sup>a</sup>(its) mask,
- 15 (2) etching the upper magnetic pole layer using the oxide film layer as <sup>a</sup>(its) mask,
- (3) etching the seed layer using the oxide film layer or the upper magnetic pole layer as <sup>a</sup>(its) mask,
- (4) etching the gap layer using the oxide film layer and the upper
- 20 magnetic pole layer, and
- (5) trim-etching the shield layer using the oxide film layer and the upper magnetic pole layer as <sup>a</sup>(its) mask; and then

executing a corrosion prevention treatment for removing a residual chlorine compound deposited on an etched surface.

25

According to still another aspect of the invention <sup>in</sup> ~~(of)~~ the method of manufacture of the magnetic head described above, any



portions of the plasma process steps (1)-(5) may be selected, combined and executed sequentially, and after that the corrosion prevention treatment for removing the residual chlorine compound may be executed.

5 According to <sup>a further</sup> ~~furthermore~~ aspect of the invention described above, <sup>the</sup> steps of rinsing and drying for removal of residual chlorine components and deposits on the side wall may be executed after each step of the plasma process steps (1)-(5), which are continuously executed in a single apparatus.

10 According to still another aspect of the invention ~~of~~ the method of manufacture of the magnetic head described above, ~~the~~ ~~(method)~~ is characterized in that the etching process of step (1) is executed using a gas which contains mainly BCl<sub>3</sub> or fluorine, steps (2) and (3) are executed using a gas which contains mainly chlorine, step (4) is executed using a gas which contains mainly BCl<sub>3</sub> or fluorine, and step (5) is executed using a gas which contains mainly chlorine, in order to increase <sup>the</sup> ~~a~~ selectivity ratio between the mask and under-layers during each etching processing step.

20

#### BRIEF DESCRIPTION OF THE DRAWINGS

The other features and advantages of the invention will be apparent from the following description taken in connection with the accompanying drawings, in which:

25 Fig. 1 is a ~~(schematic)~~ diagram <sup>showing a top view of</sup> ~~(indicating)~~ one embodiment of the invention;

Fig. 2 is a ~~(cross-section)~~ <sup>diagram showing a front view of</sup> units in <sup>a</sup> vacuum of <sup>apparatus in</sup> Fig. 1;

Fig. 3 is a [schematic] <sup>showing a</sup> diagram [in] cross-section of an etching chamber;

Fig. 4 is a perspective view in part of the etching chamber of Fig. 3;

5 Fig. 5 is a diagram for explaining a <sup>process flow</sup> [part] of the embodiment of the invention;

Fig. 6 is a [schematic diagram in] <sup>view</sup> perspective of a magnetic head according to the invention;

10 Fig. 7 <sup>is a flow diagram showing the process of</sup> [illustrates] forming [of] an upper magnetic pole by [a] three-layer resist etching according to the invention;

Fig. 8 <sup>is a flow diagram showing the</sup> [illustrates] vertical forming of a seed layer of Ni-Fe, a gap layer of Al<sub>2</sub>O<sub>3</sub>, and a shield under-layer of NiFe of the invention;

15 Fig. 9 <sup>is a process flow diagram of</sup> [illustrates] another embodiment of the invention <sup>, showing</sup> [and] its steps of manufacture;

Fig. 10 <sup>is a diagram which illustrates</sup> [explains] an advantage and effect of rinsing of the invention;

Fig. 11 <sup>is a table which</sup> [shows] a result of experiments according to the invention; and

20 Fig. 12 <sup>is a table which compares the results of the present invention to results obtained using a milling process.</sup>

#### PREFERRED EMBODIMENT

An embodiment of the invention will be described more in detail with reference to the accompanying drawings [in the] [following].

25 Figure 1 shows a schematic arrangement of one embodiment of the invention, and Fig. 2 shows a cross-section of portions <sup>in the arrangement</sup> in vacuum of Fig. 1. In these figures, an apparatus for processing

specimens according to the invention is provided with an etching process unit 1, a vacuum transport unit 2, a load lock chamber 3, an unload lock chamber 4, an atmospheric transport unit 5, a rinsing/drying unit 6, an atmospheric loader 7, and a cassette table 8.

As etching process unit 1, an etching device for etching the specimen using <sup>a</sup>plasma in <sup>a</sup>vacuum is used. By way of example, for its plasma etching process, an induction coupling type plasma etching apparatus, <sup>a</sup>helicon type plasma etching apparatus, <sup>a</sup>two-frequency excitation parallel plane type plasma etching apparatus, <sup>a</sup>microwave plasma etching apparatus or the like are adopted.

Figure 3 is a schematic diagram <sup>illustrating the</sup> [indicating] etching process unit 1 of the invention, and Fig. 4 is a perspective view of the etching process unit 1.

With reference to Fig. 3, etching process unit 1 is provided with: an etching process chamber 11 <sup>with the form of an</sup> [which is constructed by] alumina ceramic or quartz bell jar 10; specimen stage 12; process gas inlet portion 13; vacuum exhaust portion 14; and induction coil 15 (for example, of 13 MHz, 2kW), wherein on specimen stage 12, an article 18 such as a magnetic pole material to be processed is mounted, which will be described later. Further, a high frequency unit 16 capable of outputting, for example, 800kHz, 200W is connected to the specimen stage 12.

With reference to Fig. 1, rinsing/drying unit 6 is provided with rinsing cup 21, hot plate 22 and transfer device 23. For water rinsing, a spinning type wet process device is used.

In the spinning wet process device for [use of] rinsing, the specimen after post treatment undergoes, for example, water spinning rinsing or chemical solution spinning, rinsing followed by water spinning rinsing. In this case, <sup>the</sup> [its] chemical solution is selected appropriately depending on <sup>the</sup> [a] type of material to be removed from the specimen after post-treatment. Further, as its process atmosphere, <sup>an</sup> inactive gas atmosphere such as nitrogen gas or the like, or even air may be used. Also, after this wet processing, a drying process by water spinning or the like may be adopted.

As its drying process device, a dryer for drying the specimen after <sup>it has</sup> [having] been subjected to wet processing in the wet process device by heating the same, or a blower for drying the specimen by blowing a dry gas or the like, is used. Further, as its process atmosphere, nitrogen gas or air may be used.

Vacuum transport unit 2 <sup>operates</sup> [has a function] to transport a processed specimen between a process station (not indicated) of etching process unit 1 and load lock chamber 3 or unload lock chamber 4. Atmospheric transport unit 5 <sup>operates</sup> [has a function] to transport the processed specimen between load lock chamber 3 or unload lock chamber 4 and rinsing/drying unit 6. Transport device 23 <sup>operates</sup> [has a function] to transfer a wet-processed specimen between a process station (not indicated) of the wet process unit and a process station (not indicated) of the drying process unit. As <sup>the</sup> [its] specimen transport device, any prior art transport <sup>device</sup> [devices] may be adopted, including, for example, those having a gripper to grip a specimen at its periphery, a scoop to hold the specimen

thereon, a magnetic chuck, a vacuum chuck or the like each attached to an arm which is mechanically, electrically or magnetically actuated, a belt transport device wound around a main drive roller and a follower roller, or <sup>an</sup> air blower transport device may be used.

5 Vacuum transport unit 2 is arranged such that, when the etching process unit 1 is a device which processes the specimen using plasma in <sup>a</sup> vacuum, the processed specimen is ensured to be transported without being exposed to <sup>the</sup> atmosphere, with the same being contained in <sup>a</sup> vacuum.

10 Atmospheric transport unit 6 has also a function to transport the specimen which is transported from unload lock chamber 4 to dryer unit 6 and <sup>to be</sup> dried (up) therein such that the specimen is collected by cassette 8 which is mounted on cassette table 9.

15 In case the etching process unit 1 is a device which processes a specimen using plasma in <sup>a</sup> vacuum, a specimen's processing atmosphere in etching process unit 1 and a space through which a specimen to be processed is transported or a space through which a specimen having been processed is transported are  
20 arranged to be communicative with each other and/or interruptible. Further, the space through which the specimen is transported, <sup>the</sup> specimen's wet process atmosphere in the wet processing unit, a space through which a wet-processed specimen is transported, <sup>the</sup> specimen's drying process atmosphere in the dryer unit, and a  
25 space through which a drying processed specimen is transported may be arranged to be <sup>in communication</sup> [communicative] with each other or interruptible.

A process station is provided in etching process unit 1.

~~In the case where etching process unit 1 is a device, which~~  
 processes the specimen using plasma in<sup>a</sup> vacuum, its process station  
 is a specimen stage 12. One or a plurality of specimens may be  
 5 mounted on this specimen stage 12.

If etching is to applied to a plurality of lamination films  
 sequentially, and a liquid rinsing is required for removing  
 residual deposits on the etched side wall after each etching step,  
 the specimen delivered from the hot plate is transported again  
 10 to the load lock chamber without being collected by the cassette.

With reference to Fig. 5, specimen transport devices such  
 as vacuum transport device 2<sup>and</sup> atmospheric transport device 5 are  
 provided between etching process unit 1, rinsing/drying unit 6  
 and atmospheric loader 7. Vacuum transport unit 5 has a vacuum  
 15 transport chamber in which a vacuum transport robot (not  
 indicated) is provided.

In the case where the seed layer, the gap layer and the shield  
 layer are to be processed continuously, and at the same time [each]  
 corrosion prevention/deposit removal processing is to be applied  
 20 after each step of the above, the specimen is returned from the  
 atmospheric loader 7 to the vacuum transport unit 2 in repetition  
 as indicated in Fig. 5.

Now, an example of a specimen where a magnetic pole of a  
 magnetic head is to be formed will be described in the following.

25 With reference to Fig. 6, an example of a typical magnetic  
 head is shown. Magnetic head 31 is comprised of a write head 32  
 and a read head 33, and this write head 32 has an upper magnetic

pole 34, a coil 35 and an upper shield 36 while the read head 33 has a GMR read head 37, a lower magnetic pole 38 and a lower shield 39, wherein the upper magnetic pole 34 and the lower magnetic pole 38 are manufactured in a manner to be described in the following.

5 By way of example, <sup>the</sup> [an] <sup>the</sup> arrow [mark] in Fig. 7 indicates <sup>the</sup> [a] direction of disk slide.

The invention is preferably applied to <sup>the</sup> manufacture of a device having a <sup>laminated</sup> [lamination] structure with an alloy layer of Fe-Ni or Ni-Fe-Co. The invention will be described in the following by way of example, <sup>for the</sup> [of] <sup>laminated</sup> manufacture of a [lamination] structure having at least one layer of FeNi alloy and a photo resist layer as its mask, if necessary, which is etched by <sup>a</sup> gas plasma which contains a process gas such as chlorine in <sup>the</sup> etching process chamber 11.

15 With reference to Fig. 7, steps of forming an upper magnetic pole by the three layer resist etching <sup>process will be</sup> [are] described with respect to each <sup>from</sup> [mode] <sup>the</sup> of structures from D1 to D6 and each step thereof from S1 to S5. A specimen used here is comprised of <sup>an</sup> upper photo resist (PR) layer 41 <sup>which is</sup> [of] 0.5-1.0  $\mu\text{m}$  thick, <sup>a</sup> hard mask layer 42 <sup>which is</sup> [of] 1000-4000 Å thick made of  $\text{SiO}_2$  or alumina ( $\text{SiO}_2$  is shown in Fig. 7), <sup>a</sup> lower photo resist layer 43 <sup>which is</sup> [of] 2-6  $\mu\text{m}$  thick, and <sup>a</sup> seed layer 44 <sup>and is</sup> [of] 1000-3000 Å thick, made of NiFe alloy (shown as under-layer NiFe layer in Fig. 7).

In step S1, PR layer 41 is exposed to form a mask pattern.

25 Then, in step S2,  $\text{SiO}_2$  film 42 undergoes <sup>an</sup> etching process. <sup>The</sup> [A] width of <sup>the</sup> etching in this case is, for example, 0.4  $\mu\text{m}$ .

The PR layer which is, for example, 4  $\mu\text{m}$  thick is subjected to vertical etching in step S3. Thereby, a resist deep groove etch

plating frame is formed. Namely, the lower photo resist layer is plasma-etched using a gas which contains chlorine and with the hard mask layer used as its mask so as to form<sup>a</sup> deep groove 45 until a part of<sup>the</sup> seed layer 44 is exposed in the bottom of the deep groove.

- 5 In order to remove residual chlorine components deposited in the bottom of the deep groove and on an exposed surface of<sup>the</sup> NiFe alloy as indicated in D4, liquid rinsing and drying processes are applied in step S4.

Detection of a stop point in<sup>the</sup> etching process in step S2 is carried out by sensing<sup>the</sup> plasma emission in<sup>the</sup> etching process chamber 1, transmitting<sup>a</sup> (its)<sup>a</sup> signal via<sup>a</sup> glass fiber 20 which is attached thereto to a spectrometer 19, and extracting a spectroscopic emission line, for example, of SiF. Namely, when etching approaches its terminal point, <sup>the</sup> [a] level of emission of SiF drops, which drop can be detected and used for determination of the<sup>stopping</sup> (stop) point thereof. Likewise, a <sup>stopping</sup> (stop) point in step S3 can be determined, for example, by an emission line of CN when CO gas or N2 gas is added to its etching gas.

10

15

After that, Ni-Fe alloy is embedded in the deep groove by plating, CVD or sputtering methods, which is connected to seed layer 44 to form an upper magnetic pole (NiFe layer 46 shown in Fig. 7 is formed by plating).

20

In Fig. 8, a method of vertical etching of seed layer 44, gap layer 47 and shield layer 48 is indicated with respect to <sup>forms</sup> (modes)<sup>a</sup> of<sup>the</sup> structures from D6 to D10 and steps from S6 to S11 corresponding thereto. For <sup>the</sup> (an) example <sup>shown in</sup> (of) Fig. 8, a NiFe layer is used as <sup>a</sup> (its)<sup>a</sup> seed layer, Al2O3 layer is used as <sup>a</sup> (its)<sup>a</sup> gap layer and a NiFe

25



under-layer is used as <sup>a</sup>(its) shield layer.

In Fig. 8, lamination layer 51 is formed by shield layer 48 made of NiFe alloy, upper magnetic pole 50 made of NiFe alloy connected with shield layer 48, gap layer 47 made of <sup>an</sup>oxide film in close contact with <sup>the</sup>seed layer 44, and shield layer 48 made of NiFe alloy connected to <sup>the</sup>gap layer 47.

Seed layer 44 becomes an upper magnetic pole adhesion layer, and gap layer 47 is formed by an oxide film such as alumina, SiO<sub>2</sub>/TaO or the like.

<sup>A</sup>Cr-containing NiFe alloy adhesion layer, prior to forming a magnetic head layer, is subjected to plasma etching using a gas comprising chlorine gas and a rare gas such as argon in step S6. In this step, a vertical etching of <sup>the</sup>seed layer 44 using upper magnetic pole 50 as its mask is carried out. Subsequently, a corrosion prevention treatment is applied by liquid rinsing in order to remove residual etching products and residual chlorine components in step S7.

If gap layer 47 is alumina, it is subjected to plasma etching with a BCl<sub>3</sub>/Cl<sub>2</sub> gas in step S8. In this case, it means that vertical etching of gap layer 47 is carried out using upper magnetic pole 50 as its mask. If gap layer 47 is SiO<sub>2</sub>, <sup>the</sup>(its) plasma etching is <sup>performed</sup>(done) using fluorine gas. After that, corrosion prevention treatment is applied by liquid rinsing in order to remove residual etching products and chlorine components deposited on sidewalls in step S9.

Then, in step S10, trim-etching is applied to shield layer 48 by plasma etching using chlorine gas. It means that in this

step a vertical etching of the shield layer is carried out using upper magnetic pole 50 as its mask. By this trimming, an intermediate magnetic pole 49 which has the same cross-section as that of upper magnetic pole 50 can be formed.

5 Subsequently, in step S11, a corrosion prevention treatment is applied by liquid rinsing in order to remove residual etching products and chlorine components.

Immediately after the etching process using<sup>a</sup> gas plasma (of the first step), that is, within 5 minutes, the liquid rinsing  
10 (of the second step) is carried out sequentially to prevent corrosion.

This gas plasma can be generated using at least one of  $\text{BCl}_3$ , Ar and  $\text{O}_2$ , or <sup>a</sup>(in) combination therebetween, besides chlorine gas, as described above.

15 The gas plasma etching process of the invention is carried out at a temperature below  $150^\circ\text{C}$  to room temperatures, or lower than that.

The second step of the invention includes one or more than two of the following steps:

- 20 (A) pure water rinsing,  
(B) alkaline solution cleaning followed by water rinsing,  
(C) acid solution cleaning followed by water rinsing,  
(D) fluorine nitric acid cleaning followed by water rinsing, and  
(E) neutral detergent cleaning followed by water rinsing.

25

Heat drying in rinsing/drying unit 6 is conducted using hot plate 22 the temperature of which is kept below  $200^\circ\text{C}$ .

At least one of the following layers is included in the lamination layer other than the NiFe alloy layer, which is to be etched by gas plasma in the process chamber:

- (A) a photo resist layer
- 5 (B) alumina (Al<sub>2</sub>O<sub>3</sub>) layer,
- (C) silicon oxide layer,
- (D) Cu layer, and
- (E) Ta layer.

10 The substrate of the invention described above is Al<sub>2</sub>O<sub>3</sub>/TiC substrate, on which the layer of NiFe alloy is formed, which is subjected to the gas plasma etching in the process chamber.

As to the lamination layer of the upper magnetic pole 50 comprising the PR layer/Al<sub>2</sub>O<sub>3</sub> or SiO<sub>2</sub> layer/seed layer made of NiFe alloy, which are formed <sup>to be</sup> 1 μm/0.5-1.0 μm/2-4 μm thick, respectively, [of which] the Al<sub>2</sub>O<sub>3</sub> layer can be etched by <sup>a</sup> gas plasma using chlorine gas, SiO<sub>2</sub> can be etched using fluorine gas, and the seed layer made of NiFe alloy can be etched using a gas containing chlorine/argon gas. Here, the high density is defined to be 1 to 10 mA/cm<sup>2</sup> (ion saturation current density), and the low density to be 0.1 to 1 mA/cm<sup>2</sup>.

By applying corrosion prevention treatment for each lamination layer of Fig. 8, at the same time, removing etching products deposited on the side walls during the etching process, and consecutively carrying out etching process within the same process chamber, an excellent vertical etching <sup>according to</sup> (of) the invention

becomes possible.

Alternatively, if <sup>the</sup> (a) thickness of the deposits on the side wall is not too thick, <sup>the</sup> (it may be arranged such that) respective steps in Fig. 8 of S6 for etching the seed layer, S7 for etching the gap layer, and S10 for trim-etching the shield layer <sup>may be</sup> (are) executed continuously within a single or a plurality of etching units 1 without being taken out of <sup>the</sup> vacuum, and after that, a corrosion prevention treatment of S11 is applied.

For etching of <sup>the</sup> NiFe layer, a gas mainly containing chlorine is used. In this case, a large etching ratio (selectivity ratio) <sup>corresponding</sup> (respective) to the under-layer alumina film can be obtained. This is because (that), with the gas mainly containing chlorine, the alumina film is hardly etched. To the contrary, when etching the alumina film, a gas mainly containing BCl<sub>3</sub> is used. This is because <sup>and</sup> (that) a reaction of alumina  $Al_2O_3 + 2BCl_3 \rightarrow AlCl_3 + B_2O_3$  proceeds, and of which AlCl<sub>3</sub> + B<sub>2</sub>O<sub>3</sub> are evaporative in vacuum, the etching process is expedited. In this case, with BCl<sub>3</sub> gas, <sup>the</sup> (its) etching rate of NiFe film is low, therefore, a high selectivity ratio relative to the mask NiFe or underlayer NiFe films can be obtained. In the argon ion milling method, however, this stoichiometric etching mechanism does not work, thereby rendering a lower selectivity ratio in both cases of etching NiFe and alumina.

Detection of respective stop points of etching in respective steps of Fig. 8 is executed in the following manner.

When etching <sup>the</sup> NiFe layer of step S6, an emission line of Fe is monitored. When etching <sup>the</sup> alumina layer of step S8, an emission line of Al is monitored. When trim-etching <sup>the</sup> NiFe layer in step S10, its

etching time is calculated and controlled on the basis of its etching rate measured in advance.

Now, with reference to Fig. 9, an example of forming an upper magnetic pole by <sup>five</sup> layer continuous etching <sup>according to</sup> of the invention will be described <sup>with reference</sup> <sup>the structures</sup> [according] to [its structure modes] D12 to D16 and respective steps S12 to S20 corresponding thereto. <sup>The</sup> [its] specimen is a lamination layer which is comprised of: upper photo resist (PR) layer 41 <sup>which is</sup> [of] 0.5-1.0  $\mu\text{m}$  thick; hard mask layer 42 of SiO<sub>2</sub> or alumina <sup>which is</sup> [of] 2000-6000 Å thick (alumina layer is shown); upper magnetic pole layer 50 of NiFe alloy <sup>which is</sup> [of] 2-6  $\mu\text{m}$  thick (which includes the seed layer if the upper magnetic pole is formed by plating); gap layer 47 of SiO<sub>2</sub> or alumina <sup>which is</sup> [of] 1000-2000 Å thick; and shield layer 48 of NiFe alloy. In step S12, PR layer 41 is exposed to form a mask pattern. Then, in step S13, etching of hard mask layer 52 is carried out. After etching of the hard mask, a water rinsing process is carried out for removal of residual compounds deposited on the sidewall and for corrosion prevention in step S14.

Then, the upper magnetic pole layer is etched by plasma processing with a gas which contains chlorine and with the hard mask used as its mask in step S15. With chlorine gas, because its etching rate is approximately 1000 Å/min., and its selectivity ratio relative to the alumina hard mask layer is approximately 8, a thinner hard mask layer, as thin as a few thousands Å thick, will be sufficient. At the same time, because its selectivity ratio relative to the under-layer alumina gap layer is also high, <sup>very</sup> approximately <sup>as</sup> 8, it becomes easy, by carrying out over-etching

fully, to eliminate incomplete removal of etching debris resulting from uneven etching rates throughout the surfaces of the specimen.

When gap layer 47 is alumina, <sup>is employed</sup> [it is applied] plasma etching, using BCl<sub>3</sub> gas in step S17. At this instant, a part of the hard mask layer remaining on the upper magnetic pole is also removed by etching. Then, in order to remove residual deposits on the sidewall and residual chlorine components, liquid rinsing is applied in step S18. Subsequently, shield layer 48 is trimming-etched by plasma etching with chlorine gas in step S19. After that, liquid rinsing is applied in order to remove residual etching products and chlorine components in step S20.

In this invention, because NiFe alloy is included in the lamination layer, and because the high density plasma and the low energy irradiation ion method is adopted, a <sup>form</sup> (mode) of residual chlorine compound remaining after etching is considered mainly to be in a state of physical/chemical adsorption of chlorine on the surface of <sup>the</sup> alloy.

As indicated in Fig. 10, chlorine molecules exist as physically/chemically adsorbed on NiFe alloy immediately after etching. When disposed in <sup>the</sup> atmosphere, chemical reaction proceeds such that <sup>a</sup> water molecule in the air reacts with <sup>a</sup> chlorine molecule to form HCl, <sup>and</sup> [which] HCl reacts with Fe to corrode the surface of the alloy. In contrast, according to the invention, such chlorine molecules existing in the state of adsorption can be removed by dissolution into pure water and <sup>separated</sup> [separation] from the surface. Thereby, by removal of the residual chlorine components remaining

after the gas plasma etching, which can be simply enabled by the rinsing (anti-corrosion) ~~process of the invention~~, the corrosion prevention process of the invention can be achieved without any additional specific post treatment for the residual etching products.

Fig. 11 compares results of experiments obtained by the prior art and the present invention. A prior art gap layer was corroded in five minutes when disposed in air after its etching. In contrast, the gap layer which was subjected to the pure water rinsing and drying process within 2 minutes after its etching according to the invention was not corroded even after <sup>the</sup> elapse of <sup>two while disposed</sup> [2] weeks [of disposal] in air. Further, thanks to its high-density plasma etching, even at a temperature of 40°C of the specimen's stage, a high etching rate of 1000 Å/min. is achieved. Other related conditions of the experiments are also indicated in Fig. 11.

Figure 12 illustrates dimension control capabilities of the upper magnetic pole formed by the plasma etching method and the ion milling method, respectively. When [the] ion milling or low-density plasma is used, its selectivity ratio relative to the mask is low. For example, when etching Al<sub>2</sub>O<sub>3</sub>, its selectivity ratio relative to its mask material (NiFe) is 0.2-1.0. In contrast, when [the] high-density plasma is used, a high selectivity ratio of 1.0-10.0 is achieved. This is because [that] <sup>the</sup> ion energy of incidence of the specimen is as high as 500V-3 kV, thereby etching the material to be etched and the mask material non-selectively and physically all the same.

In the case where the high density plasma is used, the second high frequency power source as indicated in Fig. 3 which can supply power directly to the specimen's stage independently of the primary high frequency power source for generating the high density plasma is provided separately according to the invention, and the output from this second power supply is controlled such that the ion energy of incidence on the specimen is appropriately controlled. Preferably, its ion energy of incidence is set at a low value approximately from 50 to 500 V, and at the same time, a gas to be used is selected appropriately such as, for example, BCl<sub>3</sub> gas when etching alumina, and chlorine gas when etching NiFe alloy, in order to achieve a higher selectivity ratio for respective materials to be etched.

As described hereinabove, in the milling method, because of its lower selectivity ratio, an initial length of its upper magnetic pole at the start of etching must have a longer size. Namely, a large quantity of margin of etching for the upper magnetic pole must be provided. Therefore, it becomes difficult to have a precise dimensional control when forming the upper magnetic pole. Further, because of difficulty in obtaining verticality when etching the gap layer (sputtered substances tend to attach to the sidewall, resulting in a tapered shape), the specimen must be tilted in various directions when milling in order to obtain the <sup>desired</sup> verticality.

In contrast, according to the one embodiment of the invention, by provision of the steps of etching the lamination layer including the seed layer, gap layer and shield layer by the



high density plasma process exclusively in the vertical direction with the upper magnetic pole used as <sup>a</sup>(the) mask, and of applying the corrosion prevention treatment for removing the residual chlorine components deposited on the etched surface, it becomes possible for the gap layer to be formed to have a vertical shape as indicated in Fig. 12. Further, it also becomes possible for the intermediate magnetic pole to be formed to have the same vertical shape as that of the upper magnetic pole.

According to the invention described above, <sup>a</sup>(featuring in) <sup>a</sup>(that its) specimen which is formed from the lamination layer which includes NiFe alloy layer is etched using <sup>a</sup>(the) high density gas plasma, and then, immediately after the etching process, <sup>a</sup>(the) liquid rinsing is applied, thereby eliminating the influence of <sup>a</sup>(the) residual etching products due to ionization and providing <sup>a</sup>(the) corrosion prevention treatment simultaneously. Therefore, in the case where the specimen to be processed is an upper magnetic pole, a vertical etching of the upper magnetic pole becomes significantly easy, and in addition, its verticality is ensured to be maintained in air. Therefore, it provides <sup>a</sup>further advantage <sup>a</sup>(such) <sup>in</sup> that <sup>the</sup> [a] track width, which is one of the parameters that determine fundamental properties of the magnetic head, can be ensured to be adequately prescribed.